

Process Qualification Report

Reliability By Design

Qualification Description:

The information contained herein represents proof of Reliability and Performance of the baseline process technology listed below in accordance with the Qualification Plan and test methods referenced in Section 8.0, after exposure to a variety of environments (electrical, thermal, humidity, etc) and mechanical events that may occur during installation and operational lifetime of the product. Upon conclusion of the testing the product continued to operate within specification limits, demonstrating its capability of reliable operation throughout its lifetime.

The purpose of this report is to present Qualification Test results of the of referenced process technology. The Pericom product data presented in this report qualifies all products manufactured using the exact semiconductor materials and processing techniques used in the baseline process and its off-shoot processes. The report describes the qualification test program, procedures used, criteria enforced (at the time of product validation), and the resulting test data obtained during the Qualification Test. The materials and processing techniques used in the baseline process are incorporated into the off-shoot processes, so the quality/integrity of the baseline and off-shoots (i.e.: 2PxM, 1PxM) processes will be equivalent.

Lot Background Information:

Qual Test Date:	July-2000	By Ext. Process:	0.60um 1PxM
Process Technology:	0.60um 1P2M		
Foundry & Code:	CSM2 (C)		
Qual Test Number:	RQ98093, RQ00004	Qual Part Number:	PI5C16215A

Pericom's Qualification Test Results:

Stress Test	Test Procedure	Test Conditions	Duration	# of Lots	Samples per Lot	Results Pass/Fail
Dynamic High Temp	JESD22-A108	3000 hrs 7.0V 150°C	168 hrs	2	306	306 / 0
Operating Life		3000 hrs 7.0V 150°C	500 hrs	2	306	306 / 0
(DHTOL)		3000 hrs 7.0V 150°C	1000 hrs	2	306	306 / 0
		3000 hrs 7.0V 150°C	2000 hrs	2	306	306 / 0
		3000 hrs 7.0V 150°C	3000 hrs	2	306	306 / 0
FIT Rate			8			
Calculated MTBF			121,062,692			
High Temp Storage	JESD22-A103	1000hrs, 0V, 150°C	168 hrs	2	200	200 / 0
(HTS)		1000hrs, 0V, 150°C	500 hrs	2	200	200 / 0
		1000hrs, 0V, 150°C	1000 hrs	2	200	200 / 0
Latch Up Test	EIA JESD78	Report available by Device				
ESD-HBM Test	JESD22-A114	Report available by Device				

Qualification by Extension Information:

It is valid to use the reliability data of a particular process technology and apply to all products within this process technology family. All parts within the same family are designed to the same rules (layout & electrical), and manufacturing is controlled by SPC. Within a product family, a device can only be fabricated on one process technology option. See Appendix A for other qualified devices.

If there are any questions about this qualification, please contact Quality Support at: customerquestion@pericom.com